Search Notes		

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/694,220	KIM ET AL.	
Examiner	Art Unit	
Tianjie Chen	2627	

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Class	Subclass	Date	Examiner
369	300	6/1/2007	TJ
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INT	INTERFERENCE SEARCHED		
Class	Subclass	Date	Examiner
369	300	6/1/2007	TJ
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(INCLUDING S	RCH NOTES SEARCH STRATEGY	)
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